

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/531,203	DUAN ET AL.	
	Examiner <i>K. P.</i> Kamran Afshar, 571-272-7796	Art Unit 2617	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,181,171	02-2007	Forrester, Timothy David	455/82
*	B	US-6,832,090	12-2004	Riley et al.	455/446
*	C	US-2003/0148774	08-2003	Naghian et al.	455/456
*	D	US-5,734,982	03-1998	Endo et al.	455/450
*	E	US-2002/0082050	06-2002	Mountney et al.	455/560
*	F	US-2003/0045230	03-2003	Weissman, Haim	455/11.1
*	G	US-2003/0157943	08-2003	Sabat, John JR.	455/456
*	H	US-2003/0190919	10-2003	Niemenmaa, Jarko	455/456.1
*	I	US-2002/0032031	03-2002	Ogino et al.	455/435
*	J	US-2003/0123401	07-2003	Dean, Richard F.	370/318
*	K	US-2003/0114103	06-2003	Dinkel et al.	455/17
*	L	US-6,873,823	03-2005	Hasarchi et al.	455/11.1
*	M	US-5,937,332	08-1999	Karabinis, Peter D.	455/12.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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